Device Modeling Report

COMPONENTS:BIPOLAR JUNCTION TRANSISTOR

PART NUMBER:2SC4015 MANUFACTURER:ROHM

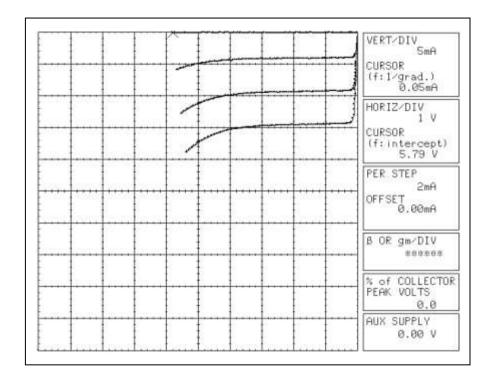


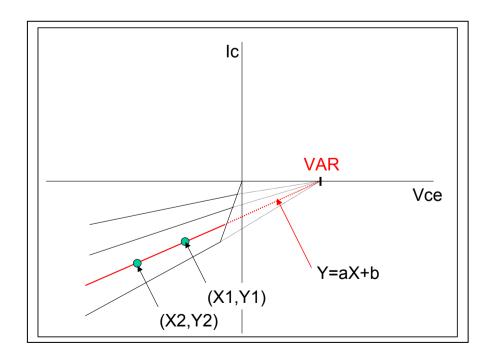
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Pspice			
model Model description			
parameter			
IS Saturation Current			
BF Ideal Maximum Forward Beta			
NF Forward Current Emission Coefficient	Forward Current Emission Coefficient		
VAF Forward Early Voltage			
IKF Forward Beta Roll-off Knee Current			
ISE Non-ideal Base-Emitter Diode Saturation Curren	ıt		
NE Non-ideal Base-Emitter Diode Emission Coefficient	ent		
BR Ideal Maximum Reverse Beta	Ideal Maximum Reverse Beta		
NR Reverse Emission Coefficient			
VAR Reverse Early Voltage			
IKR Reverse Beta Roll-off Knee Current			
ISC Non-ideal Base-Collector Diode Saturation Curre	ent		
NC Non-ideal Base-Collector Diode Emission Coefficient	cient		
NK Forward Beta Roll-off Slope Exponent			
RE Emitter Resistance			
RB Base Resistance			
RC Series Collector Resistance			
CJE Zero-bias Emitter-Base Junction Capacitance			
VJE Emitter-Base Junction Potential			
MJE Emitter-Base Junction Grading Coefficient			
CJC Zero-bias Collector-Base Junction Capacitance			
VJC Collector-base Junction Potential			
MJC Collector-base Junction Grading Coefficient			
FC Coefficient for Onset of Forward-bias Depletion			
Capacitance			
TF Forward Transit Time			
XTF Coefficient for TF Dependency on Vce			
VTF Voltage for TF Dependency on Vce			
ITF Current for TF Dependency on Ic			
PTF Excess Phase at f=1/2pi*TF			
TR Reverse Transit Time			
EG Activation Energy			
XTB Forward Beta Temperature Coefficient			
XTI Temperature Coefficient for IS			

Reverse

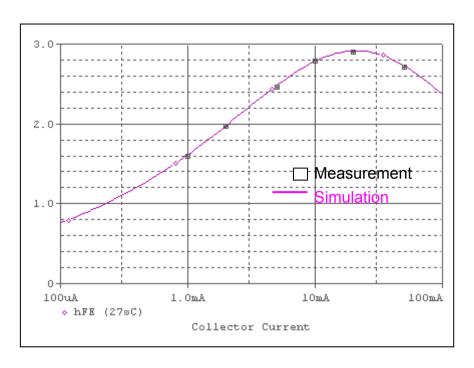
Reverse Early Voltage Characteristic





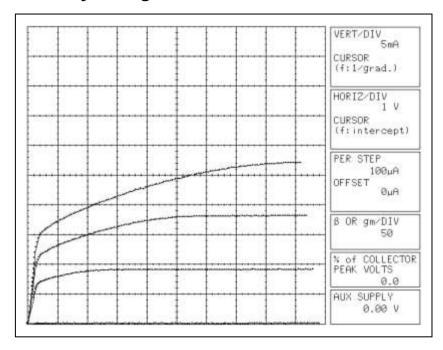
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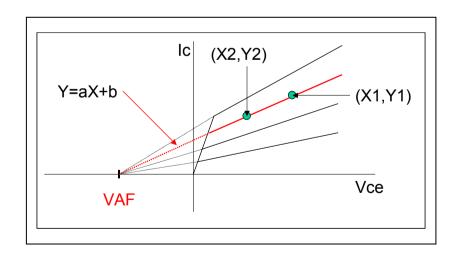
Reverse DC Beta Characteristic (le vs. hfe)



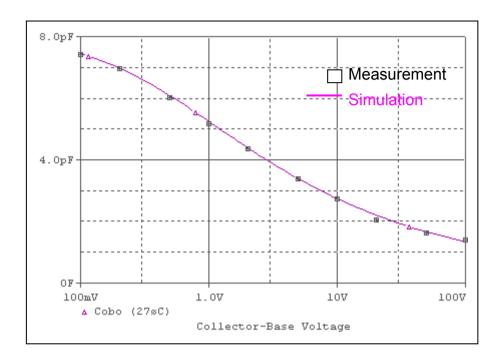
Forward

Forward Early Voltage Characteristic

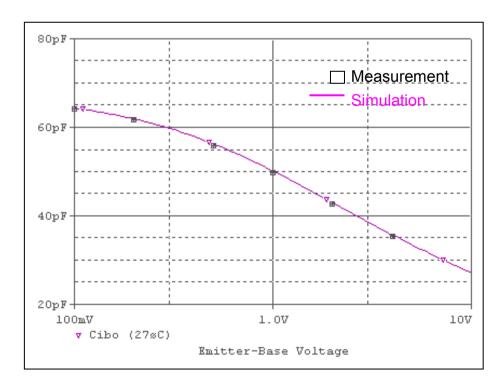




C-B Capacitance Characteristic

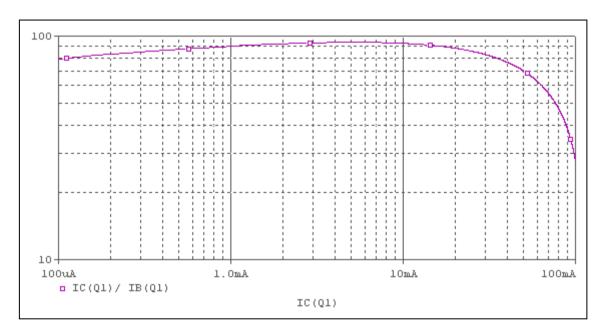


E-B Capacitance Characteristic

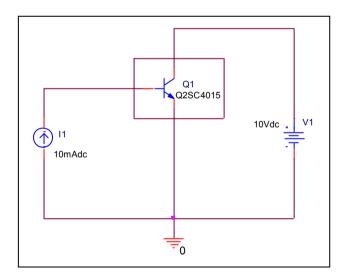


BJT Ic-hfe characteristics

Circuit simulation result

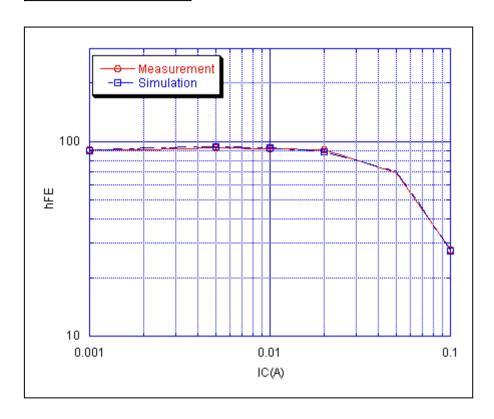


Evaluation circuit



Comparison Graph

Circuit simulation result

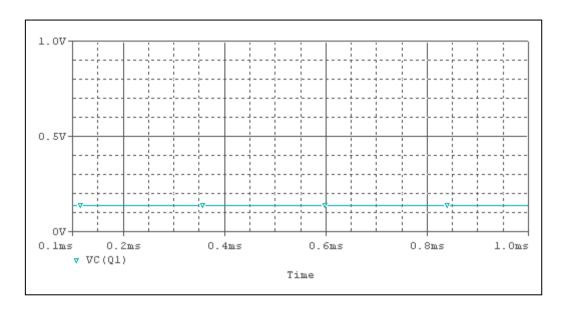


Simulation result

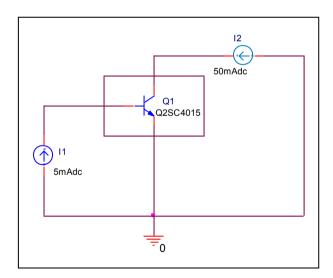
Ic(A)	hFE		%Error
	Measurement	Simulation	70E1101
0.001	90.909	90.103	0.886600887
0.002	90.909	92.317	1.548801549
0.005	92.592	93.76	1.261448073
0.01	91.743	92.807	1.159761508
0.02	90.324	88.291	2.250786059
0.05	69.252	69.61	0.516952579
0.1	27.855	27.481	1.342667385

BJT Vce(sat) voltage Characteristics

Circuit simulation result



Evaluation circuit



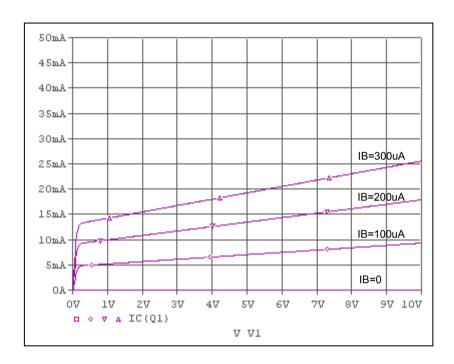
Simulation result

Test condition: IC/IB = 10, IC=50mA

Vce(sat)(V)			
Measurement	Simulation	Error(%)	
2[Max]	0.136	-	

Output Characteristics

Circuit simulation result



Evaluation circuit

